THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:

JAMES BROC STIRTON KEVIN R. LENSING HORMUZDIAR E. NARIMAN STEVEN P. REEVES

Serial No.: 10/084,987

Filed: February 28, 2002

For: METHOD OF USING HIGH YIELD SPECTRA SCATTEROMETRY MEASUREMENTS TO CONTROL SEMICONDUCTOR MANUFACTURING PROCESSES, AND SYSTEMS FOR

ACCOMPLISHING SAME

Examiner: Roy M. Punnoose

Group Art Unit: 2877

Att'y Docket: 2000.092400/TT5002

Customer No.: 23720

**PATENT** 

## RESPONSE TO OFFICE ACTION DATED SEPTEMBER 5, 2003

CERTIFICATE OF MAILING 37 C.F.R 1.8

I hereby certify that this correspondence is being deposited with the U.S. Commissioner for Patents Postal Service with sufficient postage as First Class Mail in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA P.O. Box 1450 22313-1450, on the date below: Alexandria, VA 22313-1450

Sir:

October 29, 2003 Date

This paper is submitted in response to the Office Action dated September 5, 2003, for which the three-month date for response is December 5, 2003.

No fee is believed to be due in connection with the present paper. However, the Director is authorized to deduct any fees required under 37 C.F.R. §§ 1.16 to 1.21, from Advanced Micro Devices, Inc. Deposit Account No. 01-0365/TT5002. In the event the monies in that account are insufficient, the Director is authorized to withdraw funds from Williams, Morgan & Amerson, P.C. Deposit Account No. 50-0786/2000.092400.